Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/635,636	HAINES ET AL.	
Examiner	Art Unit	
Geoffrey Mruk	2853	

	SEAR	CHED	
Class	Subclass	Date	Examiner
347	84,93	8/24/2005	GM
210	438	8/24/2005	GM
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
			1		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
Text search for filter and mesh size.	8/25/2005	GM			